

# Accuracy Estimation of DTM Using High Sampling Density Profiles

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## 1. Introduction

A digital terrain model (DTM) represents a topographic surface in terms of a set of spatial coordinates. In sampling the surface to establish a DTM, we often face on such problems: the determining of adequate sampling density in order to meet a given specifications and the evaluating of the accuracy of the obtained DTM. How accurately a topographic surface is represented by a DTM depends essentially on the such several factors: sampling density, measuring errors, interpolation method and terrain classification, etc. It is important to develop a method of the accuracy estimation and find the relationship between the accuracy and the these factors.

In the attempt to solve the problem, many experimental and theoretical investigations have been completed. F. Ackermann<sup>[1]</sup>, from his experimental research work, worked out that the main factor determining the accuracy of a DTM is the acquisition of the data, the height accuracy could be described approximately as a linear function of the average sampling interval. In 1972, B. Makarovic<sup>[2]</sup> presented the concepts of fidelity and transfer function, the transfer function can be computed according to the fidelity of different sampling density. It allows for comparative evaluation of different interpolation procedures, and also be used for planning purposes. K. Tempfli<sup>[3]</sup> applied the theory of spectral analysis to the problem of accuracy estimation. A theoretical formula was developed, in which the topographic surface was described by its spectra and measuring errors were considered. Jacobi and Frederiksen<sup>[4]</sup> also used the spectra to present the topographic relief. The spectra was showed in a Log/Log coordinates system, and was approximated by a straight line. The accuracy estimation was made based on the line.

Theoretical accuracy studies, which were based on simplifying assumptions such as homogeneity of the terrain relief, have a limited significance since these assumptions are hardly ever fulfilled. A more general approach is desirable. This article will present a method in which the high sampling density profiles are used to complete the evaluation of the accuracy of a DTM. The experiment has been carried out to judge the feasibility of the approach. The effect of measuring error are also discussed.

## 2. method

First of all, we present a theoretical formula for computing the interpolated height accuracy.

Based on the theory of spectral analysis, we can develop a formula in case of one dimension as follows:

$$\sigma^2 = \frac{1}{L} \int_0^{\infty} \left( (A(f) - R(H^*(f)))^2 + (I(H^*(f)))^2 \right) |E(f)|^2 df \quad (1)$$

$$H^*(f) = \frac{F(f)}{F_1(f)} \quad (2)$$

where:  $\sigma^2$ : variance of interpolated heights.

$2L$ : the length of sampling profile.

$F_1(f)$ : Fourier transformation of the discrete sampling heights.

$A(f)$ : the transfer function of the given interpolation method.

$R(H^*(f))$ : the real part of  $H^*(f)$ .

$I(H^*(f))$ : the imaginary part of  $H^*(f)$ .

$F(f)$ : Fourier transformation of the "true" topographic profile.

The formula (1) is different from the one of F.Tempfli. The reason is that F.Tempfli's formula was developed under the condition that sampling interval  $\Delta x$  must meet the sampling theorem, which formula (1) has no such limit.

From the spatial coordinates obtained by sampling the surface and the given interpolation method,  $A(f)$  and  $F_1(f)$  can be determined. In getting  $H(f)$ ,  $F(f)$  is desirable. But it is impossible to get  $F(f)$  because the "true" terrain is unknown in most cases.  $F(f)$  can be estimated from  $F_1(f)$ . From the knowledge of spectral analysis, we know that  $F_1(f)$  is deformed in the range of  $f \geq \frac{1}{2\Delta x}$ . Therefore, only the low frequency ( $f < \frac{1}{2\Delta x}$ ) information of  $F(f)$  can be obtained from the discrete sampling height. If we want to produce  $\sigma^2$  accurately, the spectra of topographic surface with higher frequency range is needed. This lead to our idea of using high sampling density profiles.

Let  $h_{ij}$  ( $i=0, 1, \dots, M-1, j=0, 1, \dots, N-1$ ) to be a grid DTM with the sampling interval  $\Delta x$ , which has been designed to meet an application. A direct method to get high frequency information is to increase the sampling density, that is to say, to decrease sampling interval  $\Delta x$  to  $\frac{1}{2}\Delta x$ . But in this way the total sampling points will increase four times than normal sampling procedure. It is not allowable for most applications. Instead, we can increase the sampling density only on several profiles distributed on the whole area of the terrain (called high sampling density profiles). The accuracy estimation is first made on these profiles. Then the total accuracy can be obtained according to the estimation of the profiles. In this approach, it is obvious that only little sampling work is added.

Suppose that terrain can be regarded as a homogenous surface. Let  $m_{00}^2$  to be the variance of terrain relief,  $m_0^2$  to be the variance of profile relief. Then we can get:

$$m_{00}^2 = m_0^2 \quad (3)$$

Though above formula is under the condition of homogeneity, it tell us that the variance of surface relief can be predicted using the variance of profile relief. We can anticipate that there is a relationship between the interpolation accuracy of profiles and the one of surface. It has been proved by the experiments that the relation between  $u_1$  (interpolation accuracy of profiles) and  $u_2$  (the interpolation accuracy of surface) can be expressed as follows:

$$u_2 = \sqrt{\lambda} u_1 \quad (4)$$

$$\text{or } u_2^2 = \lambda u_1^2 \quad (5)$$

Usually the topographic surface is not homogenous surface, so in formula (5) the  $u_i^2$  is always taken by the average  $u_i^2$  of several profiles.

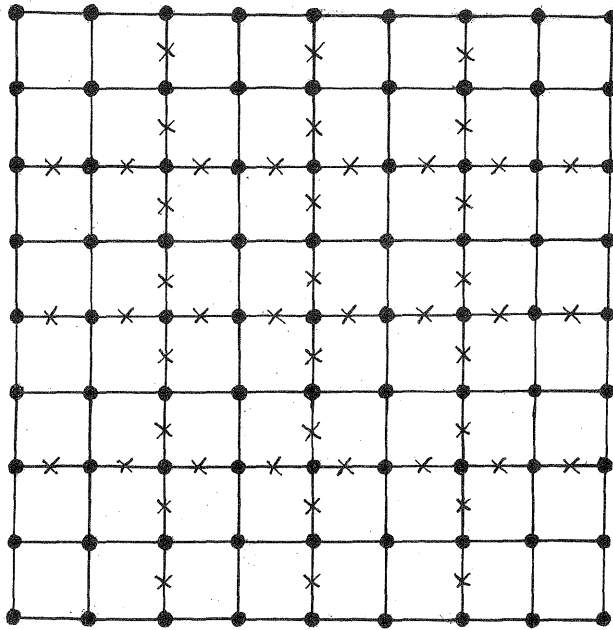


Fig.1

As showed in Fig.1, point • is the normal sampling point with the sampling interval  $\Delta x$ , corresponding height can be expressed as  $h_{ij}(i=0,1,\dots,M-1,j=0,1,\dots,N-1)$ . The profiles containing point × (point × is additional sampling point) are high sampling density profiles. The total number of high sampling density profiles is  $q$ . Each high sampling density profile contains  $N_l$  points ( $l=1,2,\dots,q$ ). The corresponding sampling interval in these profiles is  $\Delta$  ( $\Delta=\Delta x/2$ ). It means that in these profiles, the half of points are the normal sampling points, and other half are additional sampling points. The additional sampling points are used to as checking points for the computation of profile accuracy. The one dimension interpolation is applied to each high sampling density profile in the sampling interval of  $\Delta x$ . The mean error of  $l^{th}$  high sampling density profiles is calculated by the formula (6).

$$u_{i,l}^2 = \frac{1}{N_l} \sum_{j=1}^{N_l} \Delta_j^2 \quad (6)$$

( $l=1,2,\dots,q$ )

where  $\Delta_j$  is the difference between the interpolated height and "true" height.  $U_i^2$  results in the average of  $u_{i,l}^2$

$$u_i^2 = \frac{1}{q} \sum_{l=1}^q u_{i,l}^2 \quad (7)$$

One kind of arrangement of high sampling density profiles has been shown in Fig.1, Fig.2 gives another example of arranging high sampling profiles. This mode has strong control on the central part of the terrain, but weak on the edge. In our experiments, we has chosed the mode showed in Fig.1 to arrang the high samp-

ling profiles. In this mode, high sampling density profiles coincide with some of normal sampling profiles. Therefore, the additional sampling needs only little work.

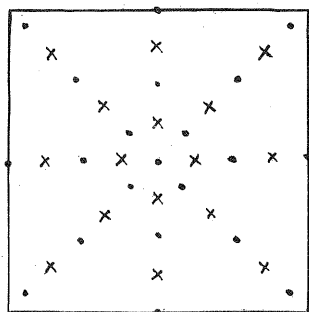


Fig. 2

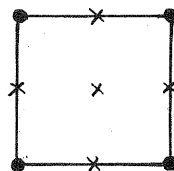


Fig. 3

We can see that, the smaller the  $\Delta$  (interval of high density profiles), the higher frequency information can we get. But with the reduction of  $\Delta$ , the total number of sampling points will increase. If  $\Delta$  is chosen to be  $\frac{1}{2}\Delta x$ , the information in the range  $f < \frac{1}{2\Delta x}$  can be obtained, the useful frequency range is twice as large as in normal sampling procedure. It has been proved that  $\Delta = \frac{1}{2}\Delta x$  is a suitable choice for accuracy estimation.

$u_2$  is defined as follows

$$u_2^2 = \frac{1}{M_x N_y} \sum_{i=0}^{M_x-1} \sum_{j=0}^{N_y-1} (f_{i,j} - \hat{f}_{i,j})^2 \quad (8)$$

where

$f_{i,j}$  is "true" height.  
 $\hat{f}_{i,j}$  is interpolated height.

$$M_x = 2M$$

$$N_y = 2N$$

that is to say, in each grid, there are 4 checking points, as showed in Fig. 3.

### 3. Experiment and Result

In our experiments, there are two kind of original data: modelling data and real data. Modelling data is expressed as D1, D2, D3, D4. The real data is expressed as T1, T2, T3. T1, T2, T3 were measured on Topocart B. The Model scale was 1:5000, while photo-scale was 1:18000. Both T1 and T2 are 41 in line and 41 in row, with sampling interval of 5 meter. T3 is a 41 x 41 DTM, with sampling interval of 20 meter. In the original data, some of the data were used as the known heights, other were regarded as checking points.

It has been proved by the test that when  $\lambda = 1.5$ , the optimal result could be got.

So formula (5) can be written as

$$u_2^2 = 1.5 u_1^2 \quad (9)$$

#### 3.1 the influence of q (the number of high sampling density profiles)

We have chosen several different q to investigate the influence of q, the result is showed in table 1. In table 1, we use

$$e = \left| \frac{\hat{u}_2 - u_2}{u_2} \right|$$

to evaluate how  $\hat{u}_2$  is close to  $u_2$ .

surface	$u_2$	q=10		q=6		q=2	
		$\hat{u}_2$	e(%)	$\hat{u}_2$	e(%)	$\hat{u}_2$	e(%)
D1	0.1398	0.1415	1.2	0.1434	2.6	0.1465	4.8
D3	0.1401	0.1415	1.0	0.1435	2.4	0.1465	4.6
D2	0.1219	0.1286	5.5	0.1258	3.2	0.1331	9.2
D4	0.1218	0.1288	5.7	0.1257	3.2	0.1331	9.3
T1	0.5873	0.5677	3.3	0.6020	2.5	0.4770	18.8
T2	0.5514	0.5577	1.0	0.5630	2.1	0.4740	14.0
T3	1.2485	1.2169	2.5	1.0298	17.5	0.8340	33.2

Table 1  
Influence of q

As to D1 and D3, there are no evident difference between the e, The same situation occurs on D2 and D4, when q is 6 and 10 respectively. But it doesn't so when q=2. When q is 6 and 10 respectively, e is almost same as to T1 and T2. But q=2 and q=6 produce quite different e. In the case of T3, q=6 and q=10 correspond to the 17.5% and 33.2% of e respectively. Modelling surface is homogenous surface, but T1 and T2 are not such surfaces. In the case of T3, left part is reservoir, the right part is mountainous region. We can conclude that we can use less number of high sampling density profiles for homogenous terrain, but more number for other kind of terrain.

### 3.2 Influence of different $\Delta x$

surface		D1	D2	D3	D4
$\Delta x=0.2$	$u_2$	0.0744	0.0744	0.0745	0.0744
	$\hat{u}_2$	0.0753	0.0751	0.0753	0.0751
	e	1.2%	0.9%	1.1%	1.0%
$\Delta x=0.4$	$u_2$	0.1398	0.1219	0.1401	0.1218
	$\hat{u}_2$	0.1415	0.1286	0.1415	0.1288
	e	1.2%	5.5%	1.0%	5.7%
$\Delta x=0.8$	$u_2$	0.2350	0.2779	0.2350	0.2778
	$\hat{u}_2$	0.2239	0.2467	0.2240	0.2472
	e	4.7%	11.2%	4.7%	11.0%

Table 2  
Influence of different  $\Delta x$

From the table 2, we can see that with the increasing of  $\Delta x$ , e slight increases, so it can be used for different sampling interval.

### 3.3 Comparison between the Tempfli's method and presented method

In order to compare the result of Tempfli's method and the method we have just presented, an experiment has been carried out. The result is showed in table 3 and table 4. In table 3 and table 4, NM stands for the new method, and TM stands for F.Tempfli's method.

It is obvious that the new method this article has presented can achieve much better estimation than F.Tempfli's. Besides, our method costs less computation time than Tempfli's. Because we only need the computation of one dimension interpolation in order to calculate the accuracy. But for Tempfli's method, two-dimension interpolation and Fourier transformation are needed. According to our experiments, Tempfli's method costs 10 times as much as our method.

$\epsilon(\%)$		D1	D2	D3	D4
$\Delta x=0.2$	NM	1.2	0.9	1.1	1.0
	TM	9.4	10.8	9.2	11.1
$\Delta x=0.4$	NM	1.2	5.5	1.0	5.7
	TM	27.1	12.1	27.2	11.9

Table 3  $q=10$

$\epsilon(\%)$	I1		I2	
	T1	T2	T1	T2
NM	3.3	1.1	1.7	3.4
TM	29.1	41.3	36.3	46.8

I1 stands for interpolation method 1.

I2 stands for interpolation method 2.

Table 4  $x=10m, q=10$

In above discussion, We haven't considered the effect of measuring error on accuracy. We'll discuss the problem in following.

#### 4. Interpolation accuracy estimation considering measuring error

Let  $h_{ij}$  be a height in a grid DTM,  $f_{ij}$  is the corresponding "true" height.

Let

$$\epsilon_{ij} = h_{ij} - f_{ij} \quad (i=0, 1, \dots, M-1, j=0, 1, \dots, N-1)$$

$\epsilon_{ij}$  is the measuring error caused by many factors. For simplicity, in our research,  $\epsilon$  is supposed to be white noise.

The effect of measuring error on the accuracy has been investigated by many experts. In B. Makrovic's opinion, the total variance  $\sigma_T^2$  can be expressed as

$$\sigma_T^2 = \sigma_0^2 + u_2^2 \quad (10)$$

where

$\sigma_0^2$  is the variance of measuring error.  
 $u_2^2$  is the variance of sampling error.

The similar formula was developed by F. Ackermann. But in formula (10), the interpolation method hasn't been taken into consideration. In following, we are going to present several formulae to estimate the accuracy considering the measuring error.

$u_2$ , the interpolation accuracy with no influence of measuring error, is defined as

$$u_2^2 = \frac{1}{M_x N_y} \sum_{i=0}^{M_x-1} \sum_{j=0}^{N_y-1} (f_{ij} - f'_{ij})^2 \quad (11)$$

$\sigma_T$ , the interpolation accuracy considering the measuring error, is defined as

$$\sigma_T^2 = \frac{1}{M_x N_y} \sum_{i=0}^{M_x-1} \sum_{j=0}^{N_y-1} (f_{ij} - z_{ij})^2 \quad (12)$$

where

$f'_{ij}$  is the interpolated height with no influence of measuring error,  $z_{ij}$  is the interpolated height with the effect of measuring error.

Let  $h_i (i=0, 1, \dots, N_L-1)$  be the sampling height with measuring error in high sampling density profiles,  $f_i$  is the corresponding "true" height. Also let  $z_i$  be the interpolated height of profiles considering measuring error,  $f'_i$  be the interpolated height with no influence of measuring error.

Let

$$\sigma_{b,l}^2 = \frac{1}{N_L} \sum_{i=0}^{N_L-1} (h_i - z_i)^2 \quad (13a)$$

$$\sigma_l^2 = \frac{1}{q} \sum_{l=1}^q \sigma_{b,l}^2 \quad (13b)$$

$$\sigma_{f,l}^2 = \frac{1}{N_L} \sum_{i=0}^{N_L-1} (f_i - z_i)^2 \quad (14a)$$

$$\sigma_f^2 = \frac{1}{q} \sum_{l=1}^q \sigma_{f,l}^2 \quad (14b)$$

$$u_{1,l}^2 = \frac{1}{N_L} \sum_{i=0}^{N_L-1} (f_i - f'_i)^2 \quad (15a)$$

$$u_1^2 = \frac{1}{q} \sum_{l=1}^q u_{1,l}^2 \quad (15b)$$

where  $\sigma_f$ : profile interpolation accuracy with the consideration of  $\epsilon$ .

$u_1$ : profile interpolation accuracy with no consideration of  $\epsilon$ .

Since  $h_i$  is the known value,  $z_i$  can be produced from the interpolation computation,  $\sigma_l$  can be got according to formula (13).  $f_{i,j}$ ,  $f_i$  is unknown.  $\sigma_T$  is the finally required result. How can we obtain  $\sigma_T$  from  $\sigma_l$ ?

We solve the question in following procedure:

- find the relation between  $\sigma_l^2$  and  $\sigma_f^2$ .
- find the relation between  $\sigma_f^2$  and  $u_1^2$ .
- find the relation between  $u_1^2$  and  $\sigma_T$ .

Considering

$$u_2^2 = \lambda u_1^2$$

if above three relations can be made out, the relation between  $\sigma_l^2$  and  $\sigma_T$  can be developed. Above procedure can be showed as follows

$$\sigma_l^2 \longrightarrow \sigma_f^2 \longrightarrow u_1^2 \longrightarrow u_2^2 \longrightarrow \sigma_T^2$$

The detail in the development of formulae is ignored, only the main formulae are presented here.

$$\sigma_f^2 = \sigma_l^2 + (a(0) - 1) \sigma_0^2 \quad (16)$$

$$a(0) = \int_{-\infty}^{\infty} H(f) df \quad (17)$$

$$u_1^2 = \sigma_f^2 - R_1 \sigma_0^2 \quad (18)$$

$$R_1 = 2 \int_0^1 |H(f) + H(2-f)|^2 df \quad (19)$$

$$\sigma_T^2 = u_2^2 + R_2 \sigma_0^2 \quad (20)$$

$$R_2 = 4 \int_0^1 \int_0^1 |H(u,v) + H(2-u,v) + H(u,2-v) + H(2-u,2-v)|^2 dudv \quad (21)$$

In formula (17) and (19),  $H(f)$  is the transfer function of one-dimension interpolation method,  $H(u,v)$  is the transfer function of two-dimension interpolation method.

From above formulae and formula (5), we can develop

$$\sigma_T^2 = \lambda \sigma_T^2 - R \sigma_0^2 \quad (22)$$

$$R = \lambda (R_1 - a(0) + 1) - R_2 \quad (23)$$

From formula (23), we know that  $R$  depends only on interpolation method.

We has arranged an experiment to judge the feasibility of formula (22) and (23). In the case of D1,  $\sigma_1^2$  was calculated with the influence of measuring error. The  $\hat{\sigma}_T^2$ , the estimation of  $\sigma_T^2$ , is calculated according to formulae (22) and (23). We use formula (12) to produce "true"  $\sigma_T^2$ . As to the given interpolation method, we have

$$\begin{aligned} R_2 &= 0.62 \\ R_1 &= 0.8 \\ a(0) &= 1.0 \\ \lambda &= 1.5 \end{aligned}$$

Then we get

$$R = 0.58$$

The result is showed in table 5.

$\sigma_0$	x=0.4				x=0.8			
	$\sigma_1$	$\hat{\sigma}_T$	$\sigma_T$	e	$\sigma_1$	$\hat{\sigma}_T$	$\sigma_T$	e
0.422	0.3747	0.3276	0.3619	9.5%	0.4043	0.3767	0.4070	7.5%
0.211	0.2133	0.2060	0.2184	5.7%	0.2589	0.2733	0.2880	5.1%
0.105	0.1469	0.1612	0.1636	1.5%	0.2059	0.2392	0.2494	4.1%

Table 5

$$e = \left| \frac{\hat{\sigma}_T - \sigma_T}{\sigma_T} \right|$$

From the table 5, we can make out that formula (22) and (23) are right.

## 5. Conclusion

This article presents a new method of estimating accuracy of DTM using high sampling density profiles. The method has been proved to be feasible for application. The effect of measuring error is also taken into consideration.

Finally, we must point out that in this new method, if only accuracy estimation is concerned, only several high sampling profiles are needed, i.e., it is not necessary to get the whole DTM. So it can be used as a method to determine the sampling interval before the acquisition of DTM. It is very useful for the establishment of LIS/GIS.

## References

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